

**HAOPIN MICROELECTRONICS CO.,LTD.**

### Description

Passivated, sensitive gate triacs in a plastic envelope, intended for use in general purpose bidirectional switching and phase control applications, where high sensitivity is required in all four quadrants.

| Symbol |                      | Simplified outline  |
|--------|----------------------|---|
| T2     | T1                   |  |
| Pin    | Description          |   |
| 1      | Main terminal 1 (T1) |   |
| 2      | Main terminal 2 (T2) |   |
| 3      | gate (G)             |   |
| TAB    | Main terminal 2 (T2) |   |

### Applications:

- ◆ Motor control
- ◆ Industrial and domestic lighting
- ◆ Heating
- ◆ Static switching

### Features

- ◆ Blocking voltage to 600 V
- ◆ On-state RMS current to 8 A

| SYMBOL      | PARAMETER                            | Value | Unit |
|-------------|--------------------------------------|-------|------|
| $V_{DRM}$   | Repetitive peak off-state voltages   | 600   | V    |
| $I_T$ (RMS) | RMS on-state current                 | 8     | A    |
| $I_{TSM}$   | Non-repetitive peak on-state current | 65    | A    |

| SYMBOL       | PARAMETER                                       | CONDITIONS  | MIN | TYP | MAX | UNIT |
|--------------|---|-------------|-----|-----|-----|------|
| $R_{thj-mb}$ | Thermal resistance<br>Junction to mounting base | Full cycle  | -   | -   | 2.0 | K/W  |
|              |   | Half cycle  | -   | -   | 2.4 | K/W  |
| $R_{thj-a}$  | Thermal resistance<br>Junction to ambient       | In free air | -   | 60  | -   | K/W  |



# BT137-600D

## Sensitive Gate Triacs

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Limiting values in accordance with the Maximum system(IEC 134)

| SYMBOL      | PARAMETER  | CONDITIONS  | MIN                | Value    | UNIT       |
|-------------|--|---|--------------------|----------|------------|
| $V_{DRM}$   | Repetitive peak off-state Voltages                           |   | -                  | 600      | V          |
| $I_{TRMS}$  | RMS on-state current   | Full sine wave; $T_{mb} \leq 102^\circ C$               | -                  | 8        | A          |
| $I_{TSM}$   | Non-repetitive surge peak on-state current                   | full sine wave;<br>$T_j = 25^\circ C$<br>prior to surge | t=20ms<br>t=16.7ms | 65<br>71 | A          |
| $I^2t$      | $I^2t$ for fusing  | $T=10ms$  | -                  | 21       | $A^2s$     |
| $dI_T/dt$   | Repetitive rate of rise of on-state current after triggering | $I_{TM}=12A; I_G=0.2A;$<br>$dI_G/dt=0.2A/\mu s$         | T2+G+              |          |            |
|             |  |   | T2+G-              | -        | $A/\mu s$  |
|             |  |   | T2-G-              | -        | $A/\mu s$  |
|             |  |   | T2-G-              | -        | $A/\mu s$  |
|             |  |   | T2-G+              | -        | $A/\mu s$  |
| $I_{GM}$    | Peak gate current  |   | -                  | 2        | A          |
| $V_{GM}$    | Peak gate voltage  |   | -                  | 5        | V          |
| $P_{GM}$    | Peak gate power  |   | -                  | 5        | W          |
| $P_{G(AV)}$ | Average gate power   | Over any 20 ms period                                   | -                  | 0.5      | W          |
| $T_{stg}$   | Storage temperature  |   | -40                | 150      | $^\circ C$ |
| $T_j$       | Operating junction Temperature                               |   | -                  | 125      | $^\circ C$ |

$T_j=25^\circ C$  unless otherwise stated

| SYMBOL                 | PARAMETER                 | CONDITIONS   | MIN                              | TYP              | MAX                      | UNIT                 |
|------------------------|---------------------------|--|----------------------------------|------------------|--------------------------|----------------------|
| Static characteristics |                           |  |                                  |                  |                          |                      |
| $I_{GT1}$              | Gate trigger current      | $V_D=12V; I_T=0.1A$  | T2+G+<br>T2+G-<br>T2-G-<br>T2-G+ | -<br>-<br>-<br>- | 2.5<br>3.5<br>3.5<br>6.5 | mA<br>mA<br>mA<br>mA |
| $I_L$                  | Latching current          | $V_D=12V; I_{GT}=0.1A$                                       | T2+G+<br>T2+G-<br>T2-G-<br>T2-G+ | -<br>-<br>-<br>- | 1.6<br>8.5<br>1.2<br>2.5 | mA<br>mA<br>mA<br>mA |
| $I_H$                  | Holding current           | $V_D=12V; I_{GT}=0.1A$                                       | -                                | 1.5              | 10                       | mA                   |
| $V_T$                  | On-state voltage          | $I_T=10A$  | -                                | 1.3              | 1.65                     | V                    |
| $V_{GT}$               | Gate trigger voltage      | $V_D=12V; I_T=0.1A$<br>$V_D=400V; I_T=0.1A; T_j=125^\circ C$ | -<br>0.25                        | 0.7<br>0.4       | 1.5<br>-                 | V<br>V               |
| $I_D$                  | Off-state leakage current | $V_D=V_{DRM(max)}; T_j=125^\circ C$                          | -                                | 0.1              | 0.5                      | mA                   |

### Dynamic Characteristics

|           |  |  |   |   |   |           |
|-----------|--|--|---|---|---|-----------|
| $dV_D/dt$ | Critical rate of rise of Off-state voltage | $V_{DM}=67\% V_{DRM(max)}; T_j=125^\circ C;$<br>Exponential wave form; $R_{GK}=1K\Omega$ | - | 5 | - | $V/\mu s$ |
| $t_{gt}$  | Gate controlled turn-on time               | $I_{TM}=12A; V_D=V_{DRM(max)}; I_G=0.1A;$<br>$dI_G/dt=5A/\mu s$                          | - | 2 | - | $\mu s$   |

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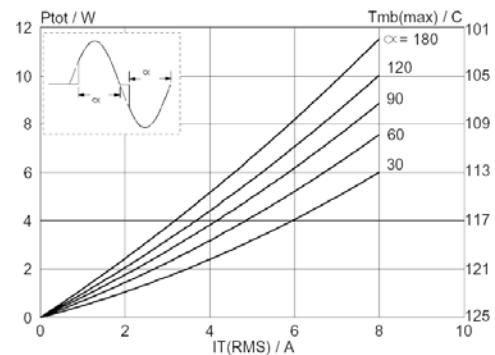


Fig.1. Maximum on-state dissipation,  $P_{tot}$ , versus rms on-state current,  $I_{T(RMS)}$ , where  $\alpha$  = conduction angle.

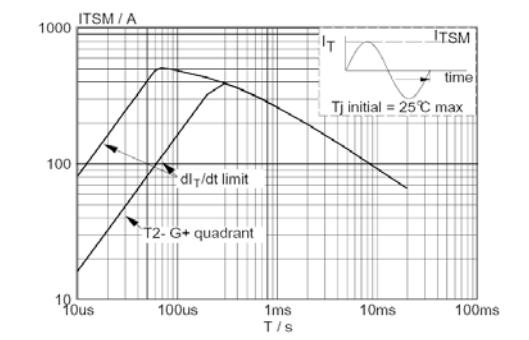


Fig.2. Maximum permissible non-repetitive peak on-state current  $I_{TS(M)}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \leq 20ms$ .

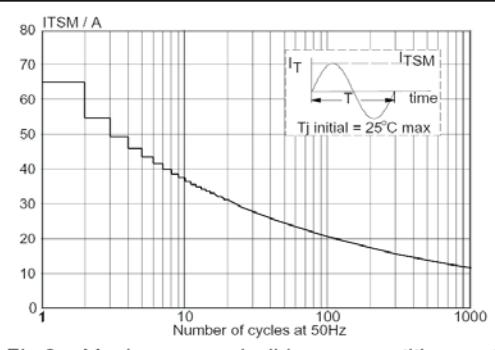


Fig.3. Maximum permissible non-repetitive peak on-state current  $I_{TS(M)}$ , versus number of cycles, for sinusoidal currents,  $f = 50$  Hz.

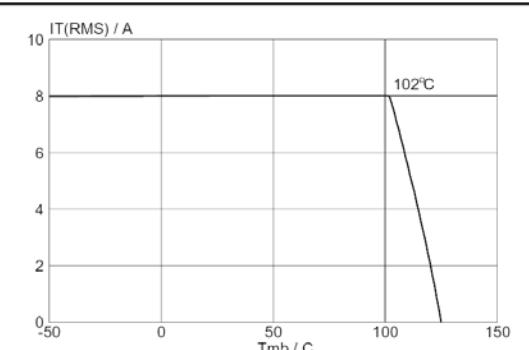


Fig.4. Maximum permissible rms current  $I_{T(RMS)}$ , versus mounting base temperature  $T_{mb}$ .

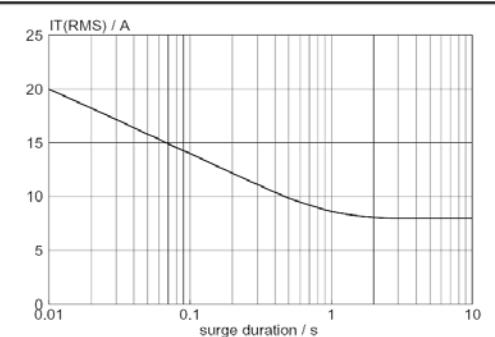


Fig.5. Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents,  $f = 50$  Hz;  $T_{mb} \leq 102^\circ C$ .

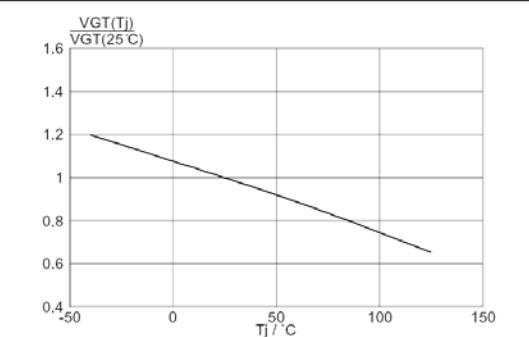


Fig.6. Normalised gate trigger voltage  $V_{GT}(T_j)/V_{GT}(25^\circ C)$ , versus junction temperature  $T_j$ .

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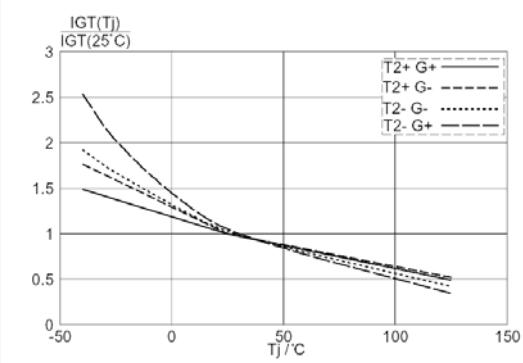


Fig.7. Normalised gate trigger current  $I_{GT}(T_j)/I_{GT}(25^\circ C)$ , versus junction temperature  $T_j$ .

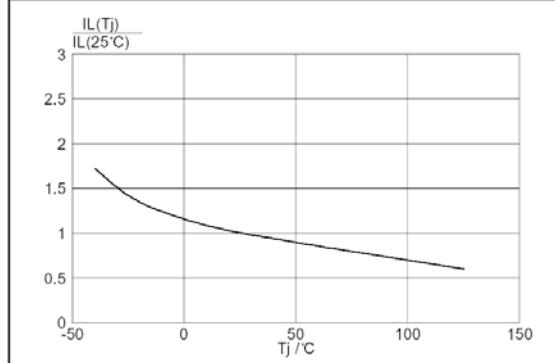


Fig.8. Normalised latching current  $I_L(T_j)/I_L(25^\circ C)$ , versus junction temperature  $T_j$ .

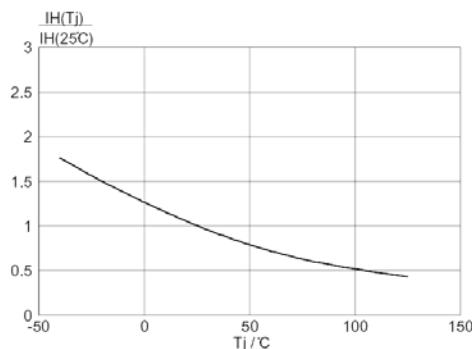


Fig.9. Normalised holding current  $I_H(T_j)/I_H(25^\circ C)$ , versus junction temperature  $T_j$ .

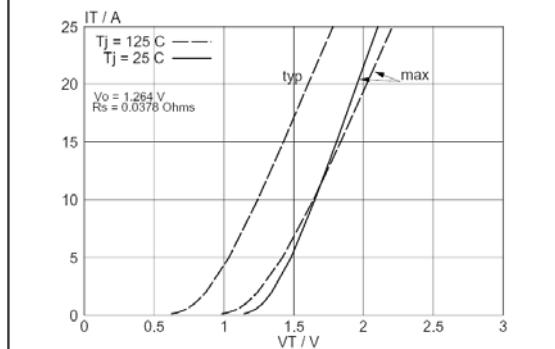


Fig.10. Typical and maximum on-state characteristic.

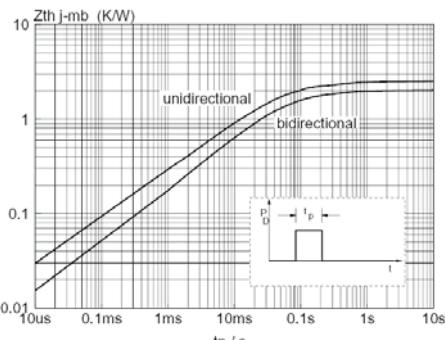


Fig.11. Transient thermal impedance  $Z_{th,j-mb}$ , versus pulse width  $t_p$ .

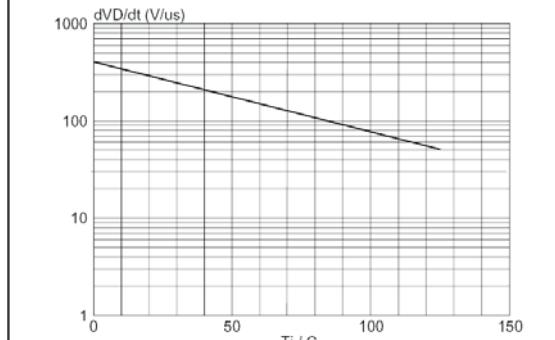


Fig.12. Typical, critical rate of rise of off-state voltage,  $dV_D/dt$  versus junction temperature  $T_j$ .

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## MECHANICAL DATA

